



Information Disclosure Statement

USSN 10/797,202

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Form PTO-1449 (Modified)	ATTY DOCKET NO. B-4127NP 621599-6	U.S. SERIAL NO. 10/797,202
LIST OF PATENTS AND PUBLICATIONS STATEMENT	APPLICANTS Paul JANKE	
	FILING DATE March 9, 2004	GROUP not yet assigned

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	ISSUE DATE	NAME	CLASS	SUB- CLASS	FILING DATE or 102(e) DATE IF APPROPRIATE
WLL	5,739,557	4/1998	O'Neil II et al.	257	192	

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

WLL	Suemitsu, T., et al., "Improved Recessed-Gate Structure For Sub-0.1- μm-Gate InP-Based High Electron Mobility Transistors," <i>Jpn. J. Appl. Phys.</i> , Vol. 37, Part 1, No. 3B, pp. 1365-1372 (March 1998).
WLL	Tanenbaum, D.M., et al., "High Resolution Electron Beam Lithography Using ZEP-520 and KRS Resists At Low Voltage," <i>J. Vac. Sci. Technol. B</i> , Vol. 14, No. 6, pp. 3829-3833 (Nov/Dec 1996).
WLL	"ZEP Series: Positive Tone, Chemically Amplified Type For Device Fabrication," Zeon Corporation INTERNET: < http://www.zeon.co.jp/products/imagelec2c2.html > 1 page total (2002).
WLL	"ZEP520" Zeon Corporation INTERNET: < http://www.zeon.co.jp/ > Version 1.02, pp. 1-11 (March 2001).

EXAMINER <i>[Signature]</i>	DATE CONSIDERED 5/13/2008
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.